intersil

Radiation Hardened Full Bridge N-Channel FET Driver

HS-4080ARH, HS-4080AEH

The HS-4080ARH, HS-4080AEH is a monolithic, high frequency, medium voltage Full Bridge N-Channel FET Driver IC. The device includes a TTL-level input comparator, which can be used to facilitate the "hysteresis" and PWM modes of operation. Its HEN (high enable) lead can force current to freewheel in the bottom two external power MOSFETs. maintaining the upper power MOSFETs off. The HS-4080ARH, HS-4080AEH is well suited for use in distributed DC power supplies and DC/DC converters, since it can switch at high frequencies.

These devices can also drive medium voltage motors, and two HS-4080ARH, HS-4080AEHs can be used to drive high performance stepper motors, since the short minimum "on-time" can provide fine micro-stepping capability.

Short propagation delays maximize control loop crossover frequencies and dead-times, which can be adjusted to near zero to minimize distortion, resulting in precise control of the driven load.

Constructed with the Intersil dielectrically isolated Rad Hard Silicon Gate (RSG) process, these devices are immune to Single Event Latch-up and have been specifically designed to provide highly reliable performance in harsh radiation environments. Complete your design with radiation hardened **MOSFETs from Intersil.**

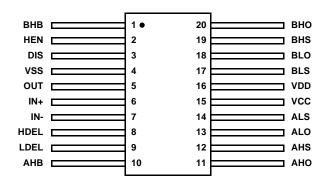
Specifications for Rad Hard QML devices are controlled by the Defense Logistics Agency Land and Maritime (DLA). The SMD numbers listed here must be used when ordering.

Detailed Electrical Specifications for these devices are contained in SMD 5962-99617. A "hot-link" is provided on our homepage for downloading.

http://www.intersil.com/spacedefense/space.htm

Pin Configuration

HS-4080ARH, HS-4080AEH (FLATPACK, CDFP3-F20) TOP VIEW



Features

- Electrically Screened to SMD # 5962-99617
- QML Qualified per MIL-PRF-38535 Requirements
- Radiation Environment
 - Gamma Dose 300kRAD(Si) (Max)
 - Latch-up Immune RSG DI Process
- Drives N-Channel FET Full Bridge Including High-Side Chop Capability
- Bootstrap Supply Max Voltage to 95V_{DC}
- TTL Comparator Input Levels
- Drives 1000pF Load with Rise and Fall Times of 50ns
- User-Programmable Dead Time
- Charge-Pump and Bootstrap Maintain Upper Bias Supplies
- · DIS (Disable) Pin Pulls Gates Low
- Operates From Single Supply 12V to 18V
- Low Power Consumption
- Undervoltage Protection

Applications

- Full Bridge Power Supplies
- PWM Motion Control

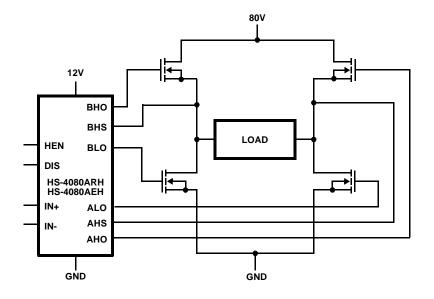
Ordering Information

ORDERING NUMBER	INTERNAL MKT. NUMBER	TEMP. RANGE (°C)
5962F9961701V9A	HS0-4080ARH-Q	-55 to +125
5962F9961701VSC	HS9-4080ARH-Q	-55 to +125
5962F9961701QSC	HS9-4080ARH-8	-55 to +125
HS9-4080ARH/Proto	HS9-4080ARH/Proto	-55 to +125
5962F9961702V9A	HS0-4080AEH-Q	-55 to +125
5962F9961702VSC	HS9-4080AEH-Q	-55 to +125

Pin Descriptions

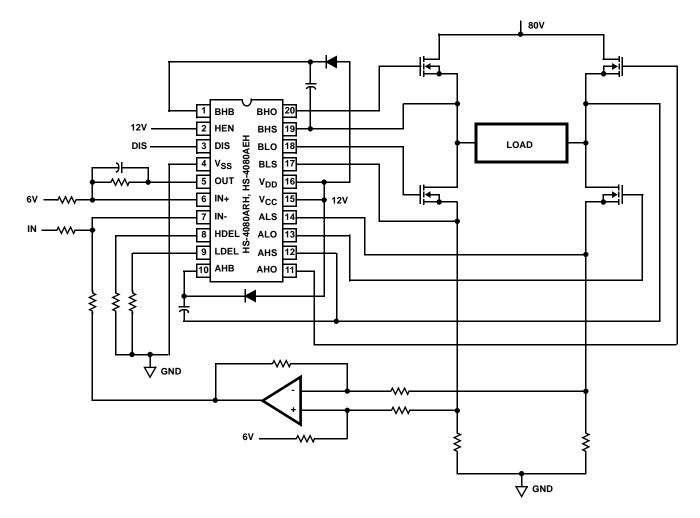
PIN NUMBER	SYMBOL	DESCRIPTION			
1	ВНВ	B High-side Bootstrap supply. External bootstrap diode and capacitor are required. Connect cathode of boot-strap di and positive side of bootstrap capacitor to this pin. Internal charge pump supplies 50µA out of this pin to main bootstrap supply. Internal circuitry clamps the bootstrap supply to approximately 15V.			
2	HEN	High-side Enable input. Logic level input that when low overrides IN+/IN- (Pins 6 and 7) to put AHO and BHO drivers (Pi 11 and 20) in low output state. When HEN is high AHO and BHO are controlled by IN+/IN- inputs. The pin can be driven signal levels of 0V to 18V (no greater than V_{DD}). An internal 100 μ A pull-up to V_{DD} will hold HEN high, so no connection required if high-side and low-side outputs are to be controlled by IN+/IN -inputs.			
3	DIS	DISable input. Logic level input that when taken high sets all four outputs low. DIS high overrides all other inputs. Whe DIS is taken low the outputs are controlled by the other inputs. The pin can be driven by signal levels of OV to 18V (in greater than V_{DD}). An internal 100 μ A pull-up to V_{DD} will hold DIS high if this pin is not driven.			
4	V _{SS}	Chip negative supply, generally will be ground.			
5	OUT	OUTput of the input control comparator. This rail to rail output signal can be used for feedback and hysteresis.			
6	IN+	Noninverting input of control comparator. This pin can only be driven by signal levels of 0V to 5.5V. If IN+ is greater than IN- (Pin 7) then ALO and BHO are low level outputs and BLO and AHO are high level outputs. If IN+ is less than IN- then ALO and BHO are high level outputs and BLO and AHO are low level outputs. DIS (Pin 3) high level will override IN+/IN- control for all outputs. HEN (Pin 2) low level will override IN+/IN- control of AHO and BHO. When switching in four quadrant mode, dead time in a half bridge leg is controlled by HDEL and LDEL (Pins 8 and 9).			
7	IN-	Inverting input of control comparator. This pin can only be driven by signal levels of 0V to 5.5V. See IN+ (Pin 6) description.			
8	HDEL	High-side turn-on DELay. Connect resistor from this pin to V _{SS} to set timing current that defines the turn-on delay of the high-side drivers. The low-side drivers turn-off with no adjustable delay, so the HDEL resistor guarantees no shoot-through delaying the turn-on of the high-side drivers. HDEL reference voltage is approximately 5.1V.			
9	LDEL	Low-side turn-on DELay. Connect resistor from this pin to V _{SS} to set timing current that defines the turn-on delay of bo low-side drivers. The high-side drivers turn-off with no adjustable delay, so the LDEL resistor guarantees no shoot-throug by delaying the turn-on of the low-side drivers. LDEL reference voltage is approximately 5.1V.			
10	AHB	A High-side Bootstrap supply. External bootstrap diode and capacitor are required. Connect cathode of boot-strap dio and positive side of bootstrap capacitor to this pin. Internal charge pump supplies 30µA out of this pin to maint bootstrap supply. Internal circuitry clamps the bootstrap supply to approximately 15V.			
11	AHO	A High-side Output. Connect to gate of A High-side power MOSFET.			
12	AHS	A High-side Source connection. Connect to source of A High-side power MOSFET. Connect negative side of bootstrap capacitor to this pin.			
13	ALO	A Low-side Output. Connect to gate of A Low-side power MOSFET.			
14	ALS	A Low-side Source connection. Connect to source of A Low-side power MOSFET.			
15	V _{CC}	Positive supply to gate drivers. Must be same potential as V _{DD} (Pin 16). Connect to anodes of two bootstrap diodes.			
16	V _{DD}	Positive supply to lower gate drivers. Must be same potential as V _{CC} (Pin 15). De-couple this pin to V _{SS} (Pin 4).			
17	BLS	B Low-side Source connection. Connect to source of B Low-side power MOSFET.			
18	BLO	B Low-side Output. Connect to gate of B Low-side power MOSFET.			
19	BHS	B High-side Source connection. Connect to source of B High-side power MOSFET. Connect negative side of bootstrap capacitor to this pin.			
20	вно	B High-side Output. Connect to gate of B High-side power MOSFET.			

Application Block Diagram



3

Typical Application (Hysteresis Mode Switching)



For additional products, see www.intersil.com/en/products.html

Intersil products are manufactured, assembled and tested utilizing ISO9001 quality systems as noted in the quality certifications found at www.intersil.com/en/support/gualandreliability.html

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Die Characteristics

DIE DIMENSIONS:

4760µm x 5660mm (188 mils x 223 mils) Thickness: 483mm ±25.4mm (19 mils ±1 mil)

INTERFACE MATERIALS:

Glassivation:

Type: Phosphorus Silicon Glass Thickness: 8.0kÅ ±1.0kÅ

Top Metallization:

Type: AlSiCu Thickness: 16.0kÅ ±2kÅ

Substrate:

Radiation Hardened Silicon Gate, Dielectric Isolation

Backside Finish:

Silicon

Metallization Mask Layout

ASSEMBLY RELATED INFORMATION:

Substrate Potential:

Unbiased (DI)

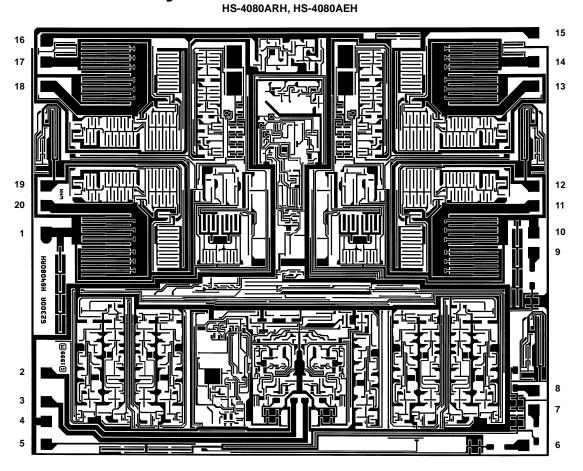
ADDITIONAL INFORMATION:

Worst Case Current Density:

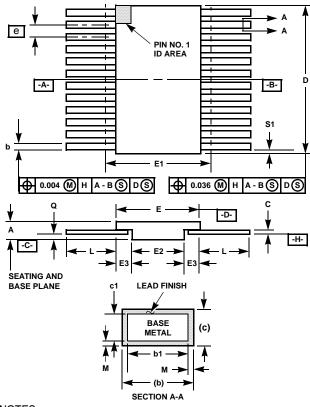
 $<2.0 \text{ x } 10^5 \text{ A/cm}^2$

Transistor Count:

432



Ceramic Metal Seal Flatpack Packages (Flatpack)



NOTES:

- Index area: A notch or a pin one identification mark shall be located adjacent to pin one and shall be located within the shaded area shown. The manufacturer's identification shall not be used as a pin one identification mark. Alternately, a tab (dimension k) may be used to identify pin one.
- 2. If a pin one identification mark is used in addition to a tab, the limits of dimension k do not apply.
- 3. This dimension allows for off-center lid, meniscus, and glass overrun.
- 4. Dimensions b1 and c1 apply to lead base metal only. Dimension M applies to lead plating and finish thickness. The maximum limits of lead dimensions b and c or M shall be measured at the centroid of the finished lead surfaces, when solder dip or tin plate lead finish is applied.
- 5. N is the maximum number of terminal positions.
- 6. Measure dimension S1 at all four corners.
- 7. For bottom-brazed lead packages, no organic or polymeric materials shall be molded to the bottom of the package to cover the leads.
- Dimension Q shall be measured at the point of exit (beyond the meniscus) of the lead from the body. Dimension Q minimum shall be reduced by 0.0015 inch (0.038mm) maximum when solder dip lead finish is applied.
- 9. Dimensioning and tolerancing per ANSI Y14.5M 1982.
- 10. Controlling dimension: INCH.

K20.A MIL-STD-1835 CDFP4-F20 (F-9A, CONFIGURATION B)
20 LEAD CERAMIC METAL SEAL FLATPACK PACKAGE

	INC	HES	MILLIMETERS		
SYMBOL	MIN	MAX	MIN	MAX	NOTES
А	0.045	0.115	1.14	2.92	-
b	0.015	0.022	0.38	0.56	-
b1	0.015	0.019	0.38	0.48	-
С	0.004	0.009	0.10	0.23	-
c1	0.004	0.006	0.10	0.15	-
D	-	0.540	-	13.72	3
Е	0.245	0.300	6.22	7.62	-
E1	-	0.330	-	8.38	3
E2	0.130	-	3.30	-	-
E3	0.030	-	0.76	-	7
е	0.050 BSC		1.27 BSC		-
k	0.008	0.015	0.20	0.38	2
L	0.250	0.370	6.35	9.40	-
Q	0.026	0.045	0.66	1.14	8
S1	0.00	-	0.00	-	6
М	-	0.0015	-	0.04	-
Ν	2	0	:	20	-

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